

# Field-Emission Scanning Electron Microscope

## JEOL JSM-6700F

- Secondary electron detector
- Semi-in-lens detector for small working distances
- Backscattered electron detector (BSE)
- Energy-dispersive X-ray spectrometer (EDXS),  
Oxford Instruments INCA 300 (detection from Be on)

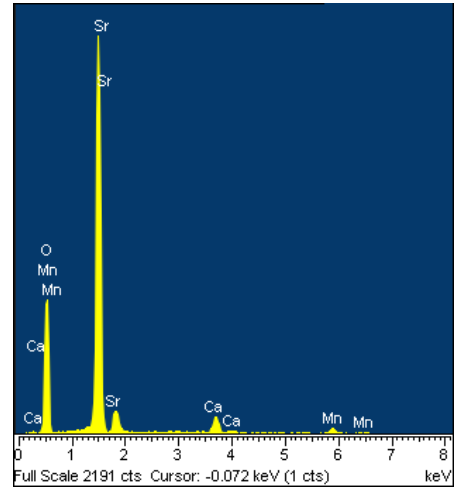
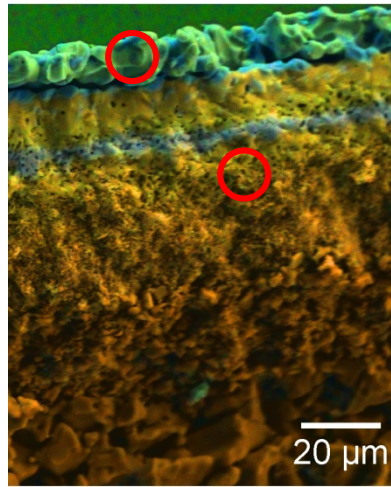
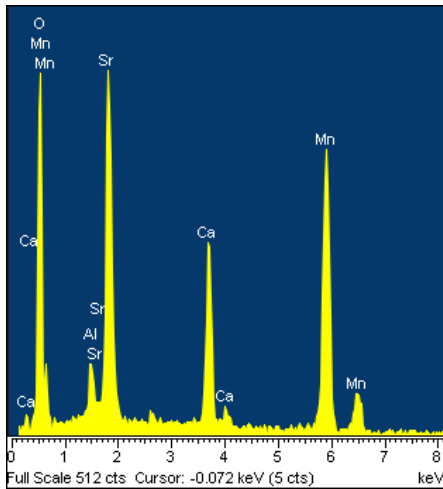
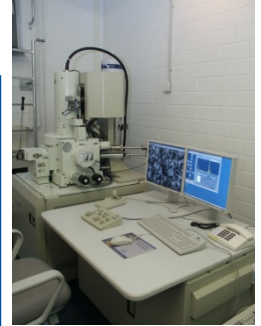
Resolving power:

1.0 nm @ 15kV

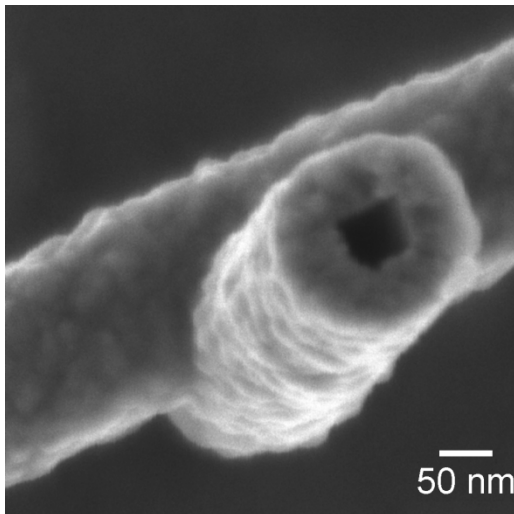
2.2 nm @ 1kV

Acceleration voltage:

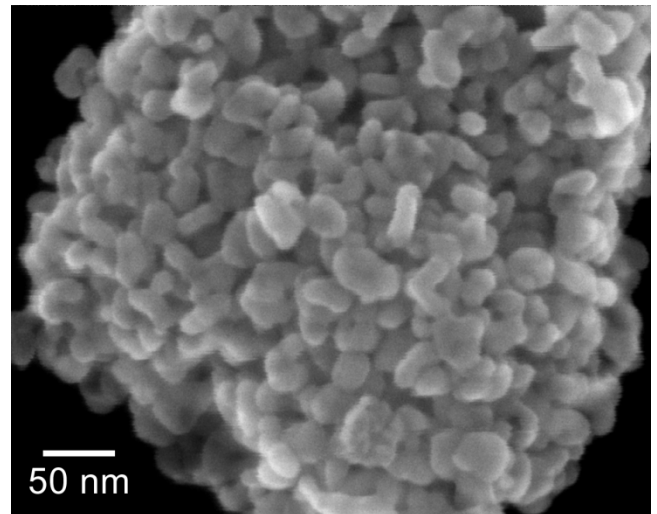
0.5 - 30 kV



Fracture surface of a perovskite tube



Crossed hollow tubes made from  $\text{TiO}_2$



Catalyst support made from  $\text{TiO}_2$  (anatase)

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